

APPLICATION NOTE



RF POWER SEMICONDUCTORS

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SUBJECT: Test result of surge tolerance for RD-series

SUMMARY:

This application note show the test results of surge tolerance for RD-series.

- Type number
 - RD01MUS1
 - RD02MUS1
 - RD07MVS1
 - RD30HVF1
 - RD30HUF1

- Conditions
 - Human model(100pF,1.5KOHM)

- Test result
 - Conditions
 - /100pF,1.5KOHM
 - /1second *3

Terminal	RD01MUS1		RD02MUS1		RD07MVS1		RD30HVF1		RD30HUF1	
GATE-SOURCE	sample No.	(V)	sample No.	(V)	sample No.	(V)	sample No.	(V)	sample No.	(V)
	#1	80	#1	100	#1	200	#1	150	#1	150
	#2	60	#2	75	#2	150	#2	150	#2	150
	#3	60	#3	75	#3	200	#3	150	#3	150
GATE-DRAIN	sample No.	(V)	sample No.	(V)	sample No.	(V)	sample No.	(V)	sample No.	(V)
	#4	220	#4	75	#4	200	#4	200	#4	150
	#5	160	#5	75	#5	200	#5	150	#5	150
	#6	150	#6	75	#6	200	#6	250	#6	250
DRAIN-SOURCE	sample No.	(V)	sample No.	(V)	sample No.	(V)	sample No.	(V)	sample No.	(V)
	#7	2500	#7	2000	#7	2500	#7	3000	#7	3500
	#8	2500	#8	3000	#8	2000	#8	3000	#8	3500
	#9	2000	#9	2000	#9	2500	#9	3500	#9	3500